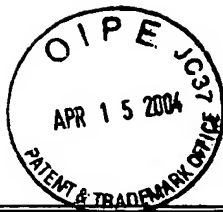




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FORM PTO-1449 LIST OF REFERENCES CITED BY APPLICANT				ATTY. DOCKET NO. VTE-141-B		SERIAL NO. 10/630,065	
				APPLICANT Donald Vandersluis			
				FILING DATE July 30, 2003		GROUP 2838	
U. S. PATENT DOCUMENT							
EXAMINER INITIALS		PATENT NO.	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE
<i>JA</i>	AA	4,520,289	5/28/1995	Sato et al.	310	316.03	
<i>JA</i>	AB	4,973,876	11/27/1990	Roberts	310	316.03	
<i>JA</i>	AC	5,543,679	8/6/1996	Morino et al.	310	316.03	
<i>JA</i>	AD	5,604,673	2/18/1997	Washburn et al.	363	147	
<i>JA</i>	AE	4,947,074	8/7/1990	Suzuki	310	316.03	
<i>JA</i>	AF	4,866,326	9/12/1989	Nikawa et al.	310	315	
<i>JA</i>	AG	5,138,217	8/11/1992	Wada et al.	310	323.21	
<i>JA</i>	AH	5,962,951	10/05/1999	Bishop	310	316.03	
<i>JA</i>	AI	6,109,245	8/29/2000	Egger et al.	123	490	
<i>JA</i>	AJ	6,133,714	10/17/2000	Hoffman et al.	320	166	
<i>JA</i>	AK	6,137,208	10/24/2000	Hoffman et al.	310	316.03	
<i>JA</i>	AL	6,147,433	11/14/2000	Reineke et al.	310	316.03	
FOREIGN PATENT OR PUBLISHED PATENT APPLICATION							
		DOCUMENT NO.	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUBCLASS	TRANSLATION
<i>JA</i>	AM	07213061	11-08-95	Japan	H02M	3/28	Yes
<i>JA</i>	AN	EP 1 067 608 A1	10.01.2001	Europe	H01L	41/04	No
<i>JA</i>	AO	WO 01/33061 A1	10.05.2001	PCT	F02D	41/20	No
<i>JA</i>	AP	WO 01/04481 A1	18.01.2001	PCT	F02D	41/20	No
	AR						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)							
<i>JA</i>	AS	A copy of the International Search Report dated October 30, 2003.					
	AT	/					
EXAMINER <i>Reynolds</i>				DATE CONSIDERED 9/17/04			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not considered. Include a copy of this form with next communication to applicant.							

FORM PTO-1449		ATTY. DOCKET NO. VTE-141-B		SERIAL NO. 10/630,065			
LIST OF REFERENCES CITED BY APPLICANT							
APPLICANT VanderSluis				FILING DATE July 30, 2003			
GROUP Unknown							
FOREIGN PATENT OR PUBLISHED PATENT APPLICATION							
		DOCUMENT NO.	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUBCLASS	TRANSLATION
PA	AL	US 2002/0121958 A1	9/5/2002	US	H01L	41/04	
PA	AM	EP 1 182 341 A1	27.02.2002	Europe	H01L	41/04	
PA	AN	EP 1 139 448 A1	04.10.2001	Europe	H01L	41/04	
PA	AO	O 841 086 A1	01.03.95	Europe	H02M	3/357	
PA	AP	WO 01/22502 A1	12.09.2000	PCT	H01L	41/00	
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)							
PA	AR	HOW TO USE INDUCTOR TYPE EMI SUPPRESSION FILTERS, 'Online, page 23 XP002266191, <URL: <a href="http://www.murata.com/emc/knowhow/pdfs/tel5ev/23e.pdf">http://www.murata.com/emc/knowhow/pdfs/tel5ev/23e.pdf</a> >, 'retrieved on 2003-12-31					
PA	AS	BIELAWSKIA John et al: "Low Profile LTCC Transformers", 2002 International Symposium on Microelectronics; Denver, Co, U.S., Sep 4-6 2002, 'Online, vol. 4931, 2002, pages 76-80, XP002266192 Proc SPIE Int. Soc Opt Eng; Proceedings of SPIE - The International Society for Optical Engineering 2002, Retrieved from the Internet: <URL: <a href="http://www.electrosience.com/publications/IMAPS2002(1).pdf">http://www.electrosience.com/publications/IMAPS2002(1).pdf</a> > retrieved on 2003-12-26, the whole document.					
	AT	/					
EXAMINER			DATE CONSIDERED			9/17/04	
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 809; Draw line through citation if not considered. Include a copy of this form with next communication to applicant.							



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FORM PTO-1449 LIST OF REFERENCES CITED BY APPLICANT				ATTY. DOCKET NO. VTE-141-B		SERIAL NO. 10/630,065	
				APPLICANT Donald VanderSluis			
				FILING DATE July 30, 2003		GROUP 2838	
U. S. PATENT DOCUMENT							
EXAMINER INITIALS		PATENT NO.	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE
<i>RA</i>	AA	4,808,874	2/28/1989	Stahlhuth	310	328	
<i>RA</i>	AB	5,333,455	8/2/1994	Yoshioka	60	533	
<i>RA</i>	AC	5,388,751	2/14/1995	Harada et al.	228	4.5	
	AD						
	AE						
	AF						
	AG						
	AH						
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	AK						
FOREIGN PATENT OR PUBLISHED PATENT APPLICATION							
		DOCUMENT NO.	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUBCLASS	TRANSLATION
<i>RA</i>	AL	JP 01185175	24-07-1989	Japan	H02N	2/00	
<i>RA</i>	AM	WO 0178160	18-10-2001	US	H01L	41/09	
	AN						
	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)							
	AR						
	AS						
	AT						
EXAMINER <i>RA</i>				DATE CONSIDERED 9/17/04			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not considered. Include a copy of this form with next communication to applicant.							



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FORM PTO-1449 LIST OF REFERENCES CITED BY APPLICANT				ATTY. DOCKET NO. VTE-141-8		SERIAL NO. 10/630,065	
				APPLICANT Donald VanderSluis			
				FILING DATE July 30, 2003		GROUP 2838	
U. S. PATENT DOCUMENT							
EXAMINER INITIALS		PATENT NO.	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE
<i>DL</i>	AA	5,465,021	11/7/1995	Visscher et al	310	328	
<i>DL</i>	AB	4,736,131	4/5/1988	Fujimoto	310	328	
<i>DL</i>	AC	2001/0030306	10/18/2001	Schrod	336	200	
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
FOREIGN PATENT OR PUBLISHED PATENT APPLICATION							
		DOCUMENT NO.	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUBCLASS	TRANSLATION
<i>DL</i>	AL	EP 0325764	02.08.89	EP	H01L	41/08	
<i>DL</i>	AM	JP 6129881	27.12.86	JP	H01L	41/08	
	AN	US 2001/0030306	10/18/2001	US			
	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)							
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	AS						
	AT						
EXAMINER <i>DL guies</i>				DATE CONSIDERED 9/17/04			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not considered. Include a copy of this form with next communication to applicant.							

\* Not found

FORM PTO-1449 LIST OF REFERENCES CITED BY APPLICANT				ATTY. DOCKET NO. VTE-141-B		SERIAL NO. Unknown	
				APPLICANT Donald VanderSluis			
				FILING DATE 29 July 2003		GROUP Unknown	
U. S. PATENT DOCUMENT							
EXAMINER INITIALS		PATENT NO.	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE
<i>AA</i>	AA	4,749,897	07/07/88	Natsume, et al.	310	317	03/11/87
<i>AB</i>	AB	5,036,283	07/30/91	Yamada, et al.	318	116	11/9/88
<i>AC</i>	AC	5,053,668	10/01/91	Mitsuyasu	310	317	01/18/89
<i>AD</i>	AD	5,130,598	07/14/92	Verheyen, et al.	310	316.03	12/14/90
<i>AE</i>	AE	5,316,013	05/31/94	Striabel, et al.	128	754	08/26/91
<i>AF</i>	AF	5,479,062	12/26/95	Yoshino	310	316.03	08/04/92
<i>AG</i>	AG	5,543,679	08/06/96	Morino, et al.	310	316.03	08/31/93
<i>AH</i>	AH	5,895,998	04/20/99	Saylor	310	316.01	09/18/97
<i>AI</i>	AI	6,133,714	10/17/00	Hoffmann, et al.	320	166	06/06/87
<i>AJ</i>	AJ	6,236,190 B1	05/22/01	Hoffman, et al.	320	166	10/25/96
	AK	_____					
FOREIGN PATENT OR PUBLISHED PATENT APPLICATION							
		DOCUMENT NO.	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUBCLASS	TRANSLATION
	AL	/					
	AM						
	AN						
	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)							
	AR	/					
	AS						
	AT						
EXAMINER <i>Requies</i>				DATE CONSIDERED 9/17/04			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not considered. Include a copy of this form with next communication to applicant.							